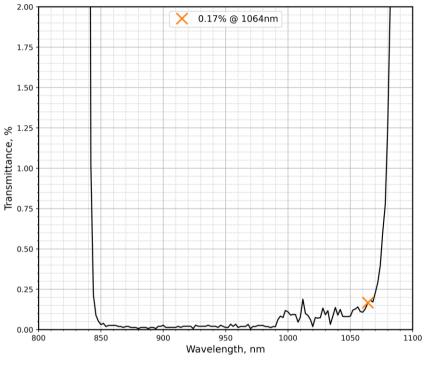


YOUR SIDEKICK FOR LASER OPTICS DEVELOPMENT



PO2174 Ts i45

Fig. 1.

SIDE MEASURED: S1 (good component)

COMMENTS:

S1: (arrow marks) Rp<2% + Ts<0,2% @ 1064 nm AOI=45 deg +/-1 deg S2: ARp<0.1%@1064 nm, AOI=45 deg

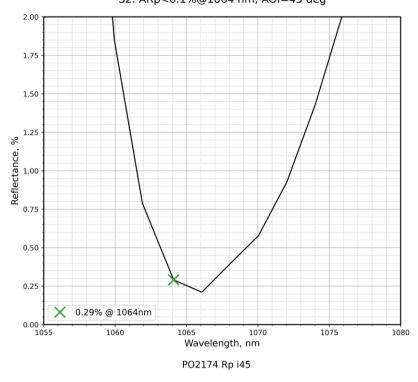


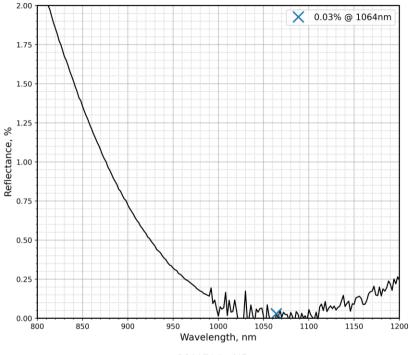
Fig. 2.

SIDE MEASURED: S1 (good component)

COMMENTS:



S1: (arrow marks) Rp<2% + Ts<0,2% @ 1064 nm AOI=45 deg +/-1 deg S2: ARp<0.1%@1064 nm, AOI=45 deg



PO2174 Rp i45

Fig3.

SIDE MEASURED: S2 only (grinded witness sample)

COMMENTS: